



MS ISSUE FEE
PATENT
0171-1026P

DFW

IN THE U.S. PATENT AND TRADEMARK OFFICE

Applicant: Satōshi OKAZAKI et al. Group: 1775
Application No.: 10/679,264 Examiner: Elizabeth D. Ivey
Filed: October 7, 2003 Conf.: 3127
For: HALFTONE PHASE SHIFT MASK BLANK, AND METHOD OF
MANUFACTURE

LETTER REQUESTING INITIALED PTO 1449 FORM

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

DEC 11 2006

Sir:

In reviewing the above-captioned application file upon allowance, the undersigned has noted that even though acknowledgement was received for the PTO Form 1449 filed on June 23, 2004, the Examiner did not initial the reference under "Other Documents". No reason was given as to why this reference was not initialed.

The Patent and Trademark Office therefore is requested to return the initialed form to the undersigned as soon as possible.

If necessary, the Commissioner is hereby authorized in this, concurrent, and future replies, to charge payment or credit any overpayment to Deposit Account No. 02-2448 for any additional fees required under 37 C.F.R. §1.16 or under 37 C.F.R. §1.17; particularly, extension of time fees.

Respectfully submitted,

BIRCH, STEWART, KOLASCH & BIRCH, LLP

By *mau (23 Nov 06)*
GERALD M. MURPHY, JR., #28,977

P.O. Box 747
Falls Church, VA 22040-0747
(703) 205-8000

GMM *(initials)*jd

APPLICATION NO.
10/679,264

APPLICANT
OKAZAKI, Satoshi et al.

FILING DATE
October 7, 2003

GROUP
1773

EXAMINER INITIAL	DOCUMENT NUMBER	Kind	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
EDJ	US 5,605,776	A	1997-02-25	Isao et al.			
	US 5,714,285	A	1998-02-03	Tu et al.			
	US 5,952,128	A	1999-09-14	Isao et al.			
	US 6,335,124	B1	2002-01-01	Mitsui et al.			
	US 2002/0058186	A1	2002-05-16	Nozawa et al.			
	US 2002/0086220	A1	2002-07-04	Nozawa et al.			
EDJ	US 2002/0122991	A1	2002-09-05	Shiota et al.			
	US						
	US						
	US						

FOREIGN PATENT DOCUMENTS

[illegible]

OTHER DOCUMENTS (Include Name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.) date, page(s), volume-issue number(s), publisher, city and/or country where published.)

Yoshioka et al., "An attenuated phase-shifting mask with a single-layer absorptive shifter", Mitsubishi Denki Giho, 1995, Japan, Vol. 69, No. 3, pp. 67-71 (XP 008030088)

DATE CONSIDERED

<p>EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>	<p> <u>Chapman P. Lugo</u> <u>6/2/70</u> </p>
--	--